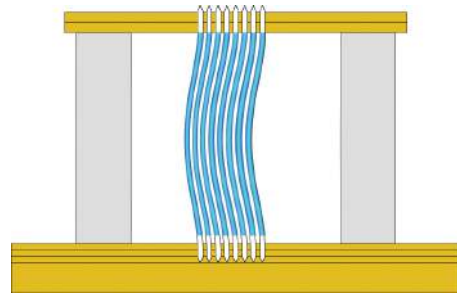
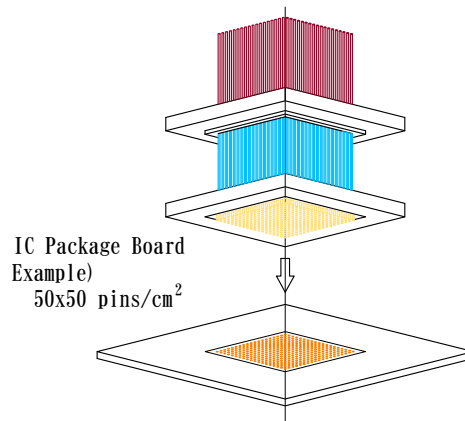


Wire Probe Narrow pitch

This Probe Pins are made from Tungsten with special plating and teflon coating. When the pin is arched, some force arises from getting back to original straight shape. This force is useful as contacting load to DUT. As a diameter of pin is so small, many pins with grid pattern is suitable for Continuity test of Semiconductors and Connecting devices



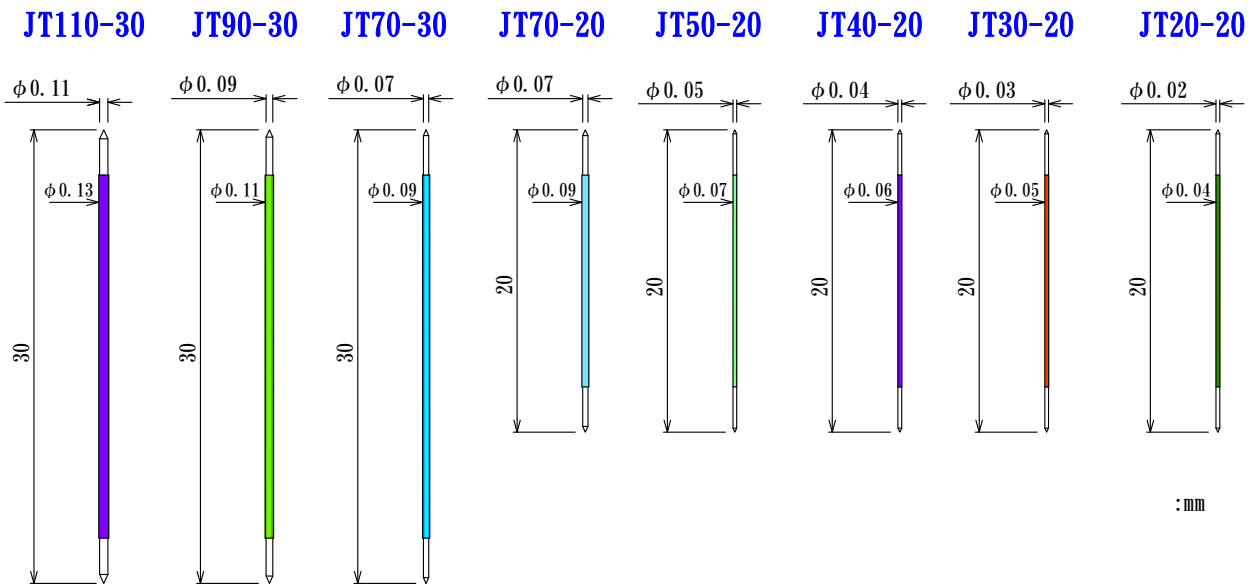
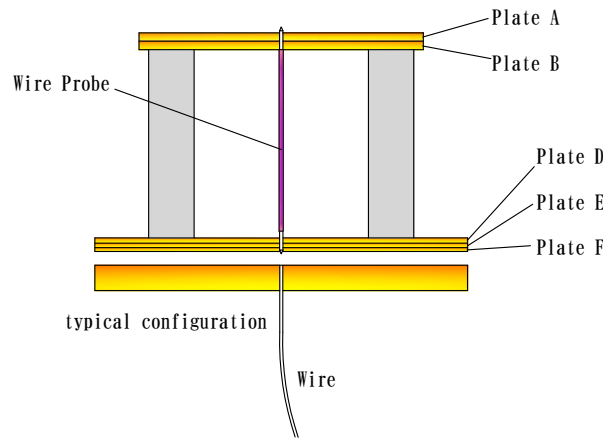
Pitch (Narrowest)
 300 μm / 11811 μinch
 150 μm / 5906 μinch
 100 μm / 3937 μinch
 80 μm / 3150 μinch
 65 μm / 2559 μinch
 55 μm / 1397 μinch
 45 μm / 1772 μinch






Application (Continuity Test etc)

- Narrow Pitch Board
- Narrow Pitch Device
- IC Package Board
- LCD Panel Test
- Various type of Connectors
- High Current Device
- Vertical type Probe Card
- Kelvin Measurement Device

Wire Probe



*Color shown is reference only. Actual color might be different.

Specifications (typical)		JT110-30	JT90-30	JT70-30	JT70-20	JT50-20	JT40-20	JT30-20	JT20-20
Pitch (min)	μm	300	150	100	100	80	65	55	45
Load	N	0.147	0.078	0.029	0.078	0.019	0.014	0.008	0.005
	gf	15	8	3	8	2	1.5	0.8	0.5
Travel (typical)	μm	250				200	150	100	100
Pin Head Style		Sphere 		Needle 			Flat 		
Pin Dia.	μm	110	90	70	70	50	42	32	22
Current Rating	mA	1100	750	500	500	250	200	150	100
Resistance	m Ω	200	450	620	430	680	900	2300	4820
Self inductance	nH	36.0	37.2	38.7	24.2	25.5	26.4	27.0	28.8
Capacitance	pF	0.41	0.21	0.15	0.10	0.12	0.13	0.14	0.13